Sear	ch Noi	tes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/709,893	LIN, AKAN	
Examiner	Art Unit	
Lev I. Iwashko	2186	

SEARCHED			
Class	Subclass	Date	Examiner
711	207	8/3/2006	LI
711	204	8/3/2006	LI
711	208	8/3/2006	LI

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		<u> </u>	

SEARCH NOT (INCLUDING SEARCH S)
	DATE	EXMR
Searched Lin Akan for possible double patenting issues.	8/3/2006	LI
Searched EAST utilizing keywords/	8/3/2006	LI
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